IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants:

Dat : October 23, 2003

Beaman et al.

Group Art Unit: 2829

Serial No.: 09/251,988

Examiner: J. M. Hollington

Filed: February 17, 1999

Docket No.: YO999-088

For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE

POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY

Commissioner for Patents P.O. Box 1450

Alexandria, VA 22313-1450

FAX RECEIVED

AMENDMENT

OCT 2 3 2003 **PETITIONS OFFICE**

In response to Office Action dated July 10, 2003, please consider the following:

O1 FC:18to

OCT 2 9 2003

OFFICE OF PETITIONS